

## USCMS Phase-2 Forward Muon Upgrade Workshop



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# Electronics Radiation Hardness and On-Chamber Electronics Control

*Wednesday, 7 December 2016 16:35 (25 minutes)*

CCB path for the slice test, eprom issues, past experiences and considerations for future electronics testing

**Presenter:** MATVEEV, Mikhail (Rice University (US))

**Session Classification:** Technical Review